



FIG.1

aging process						reliability test for 1000 hr			
Capacitance (μF)	120Hz		100KHz		120Hz		100KHz		
	ESR (mΩ)	ESR (mΩ)	leakage current (μA)	yield (%)	Capacitance (μF)	ESR (mΩ)	leakage current (μA)	yield (%)	
embodiment 1	343	98	8	204.0		344	99	7	2.96
	348	102	7	124.2		348	106	7	28.4
	351	105	8	83.8	100	354	106	7	8.48
	350	102	7	18.6		350	108	7	3.12
	349	111	7	51.0		342	111	7	4.82
	<u>349</u>	<u>119</u>	<u>7</u>	<u>296</u>		-	-	-	-
embodiment 2	353	103	8	32.9		346	105	8	3.32
	353	107	8	57.3	80	354	106	8	4.08
	357	103	8	37.3		<u>6.7</u>	<u>27130</u>	<u>7680</u>	<u>>20000</u>
	350	121	8	230		<u>345</u>	<u>122</u>	<u>7</u>	<u>481</u>

FIG. 2